



Test & Measurement Product Catalogue

July 2024

Solar Simulator



Compact and low price, the Ossila Solar Simulator is ideal for characterizing small-area solar cells, providing:

- Excellent AAA spectral distribution over a 15 mm diameter area
- ABA classification over a 25 mm diameter area (IEC 60904-9:2020 International Standard)
- Stable and reliable output, easily achieving Class A temporal stability
- Requires zero maintenance and minimal warm up time.
- Just plug it in, turn it on, and start measuring.

You can buy on its own to be easily integrated into your solar cell testing lab - or as part of our Solar Cell I-V Test Systems (available as a solar cell testing kit) to equip your laboratory with a fully integrated PV characterization system.



Spectral Tunability
Tune with powerful software



Long Lifetime
10,000 operating hours



Minimal Warm-Up Time
Ready to use and measure

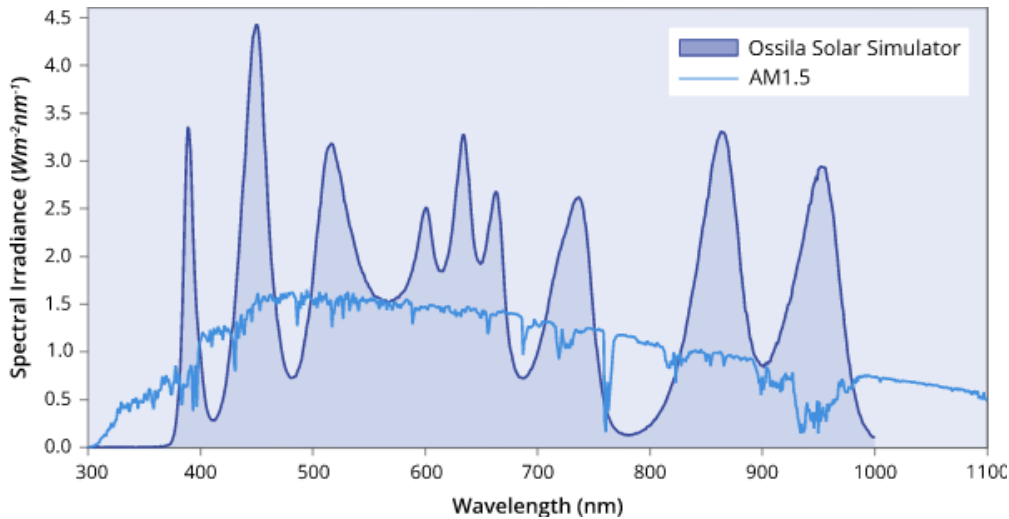


Compact Size
Portable and modular design



Easy-to-Use Software

Our free, downloadable software allows you to control the LED outputs individually as well as change the total irradiance output. You can also control the lamp using a serial command library. This can be useful for specialist measurements or non-conventional spectral output (e.g. indoor PV measurement, low light intensity conditions, etc).



| | |
|---|---------------------------|
| Classification over 15 mm diameter area | AAA |
| Type | LED-Based, Steady State |
| Spectral deviation | <70% |
| Spectral coverage | >80% |
| Working distance | 8.5 cm |
| Irradiance (at working distance) | 1000 W/m ² |
| Maximum Lamp Time | 10000 hours |
| Dimensions (head only) L x W x H | 10.5 cm x 9.0 cm x 8.0 cm |
| Weight | 600 g |

Solar Cell I-V Test System



The Ossila Solar Cell I-V Test System is a low-cost solution for reliable characterization of photovoltaic devices. The PC software (included with all variants of the system) measures the current-voltage curve of a solar cell and then automatically calculates key device properties. In addition, I-V measurements can be performed periodically over time to track the stability of these properties.

The system is available with either manual or automatic pixel switching (if you are using one of Ossila's substrate systems), or without a test board for use with your own substrate and testing system or if you already own one of our test boards. Please refer to the table under the specifications tab if you are not sure which model you should choose.



Solar Simulator Compatible
Can be combined with the Ossila Solar Simulator



User-Friendly PC Software
With 3 fully customisable measurements



Wide Measurement Range
Capable of delivering voltages between -10 V and +10 V



Measure Device Stability
Characterise performance over long time periods



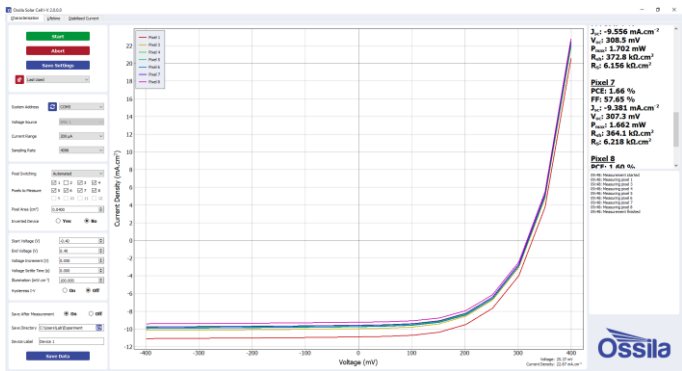
Calculates Device Properties

The included PC software automatically calculates key properties of solar cells from the measured I-V curves. These properties include: the power conversion efficiency (PCE), fill factor (FF), short-circuit current density (Jsc), open-circuit voltage (Voc), maximum power (Pmax), shunt resistance (Rsh), and series resistance (Rs).



Rapid Characterisation

If you are using one of Ossila's substrate systems, the Solar Cell I-V System can be purchased with a multiplexing test board (just select the 'automated' variant of your choice in the drop-down list), which enables automatic pixel switching. As an added bonus, the temperature and light will also be recorded during the measurement!



Voltage Specifications

| Range | Accuracy | Precision | Resolution |
|-------|----------|-----------|------------|
| ±10 V | ±10 mV | 333 µV | 170 µV |

Current Specifications

| Range | Accuracy | Precision | Resolution |
|---------|----------|-----------|------------|
| ±200 mA | ±500 µA | 10 µA | 1 µA |
| ±20 mA | ±10 µA | 1 µA | 100 nA |
| ±2 mA | ±1 µA | 100 nA | 10 nA |
| ±200 µA | ±100 nA | 10 nA | 1 nA |
| ±20 µA | ±10 nA | 1 nA | 100 pA |

Four-Point Probe



The Ossila Four-Point Probe is an easy-to-use tool for the rapid measurement of sheet resistance, resistivity, and conductivity of materials. Built with a high-specification Ossila Source Measure Unit at its core, the low-cost system has a wide measurement range.

Our four-point probe reduces the risk of damaging your delicate samples, such as polymer films with thicknesses on the order of nanometres. The probe head uses rounded, spring-loaded contacts instead of sharp needles for good electrical contact without piercing the sample.

We have curated a compact and durable design for use in busy labs where shelf space is limited. Choose the Ossila Four Point-Probe to elevate your materials characterization and thin film development programs.



Wide Current Range

Characterization of a wide range of materials



Free Software

Keeping your software up to date



Linear Translation Stage

Achieve good electrical contact every time



Characterize Large Samples

Characterize samples up to 152.4 mm diameter



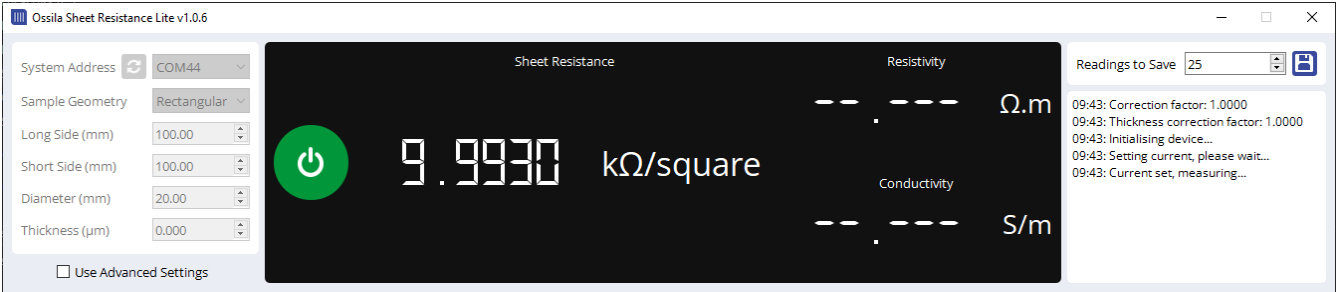
Non-Destructive Soft Contact Probes

Designed to measure delicate samples. Rounded, soft contact probes, with a 0.24 mm radius, spread the downward force applied to the sample. The probes are gold plated and mounted on springs for good electrical contact. When making contact, they retract into the head to ensure that a uniform force of 60 grams is applied.



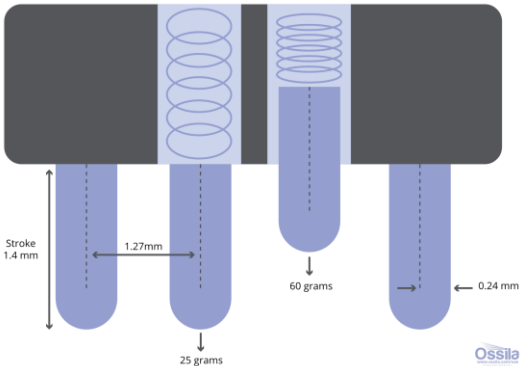
High Accuracy

Positive and negative polarity measurements can be performed to calculate the average sheet resistance between positive and negative currents. This eliminates any voltage offsets that may have occurred, hence increasing the accuracy of your measurements.



Control your four-point probe with our free, user-friendly Ossila Sheet Resistance Lite software. The software can calculate appropriate geometrical correction factors for the sample geometry and the resistivity and conductivity of the sample to allow for extensive, accurate electrical characterization of materials.

| | |
|-------------------------------|--|
| Voltage Range | ±100 μ V – ±10 V |
| Current Range | ±1 μ A – ±200 mA (5 ranges) |
| Sheet Resistance Range | 100 m Ω /square – 10 M Ω /square |
| Probe Spacing | 1.27 mm |
| Rectangular Sample Size | 5 mm – 152.4 mm |
| Circular Sample Size Diameter | 5 mm – 152.4 mm |
| Maximum Sample Thickness | 8 mm |
| Dimensions L x W x H | 240 mm x 145 mm x 150 mm |



Contact Angle Goniometer



The Ossila Contact Angle Goniometer provides a fast, reliable, and easy method to measure contact angles and surface tensions of liquid droplets. Our systems lets you achieve easier ink optimization with intuitive PC software, high quality video, and rapid image capture. Our software helps you characterize high contact angles for water resistant or protective coatings, or low contact angles for highly uniform solution coatings.

Thanks to the low price and compact size, the Ossila Contact Angle Goniometer is a great choice for any characterization setup.



Easier Ink Optimisation

Continuous feedback speeds up ink formulation



Rapid Image Capture

Study the wetting process in detail



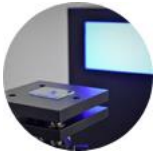
High-Resolution Video

Capture quality videos of your droplets



Free Software

Keeping your software up to date



Light Source for Accurate Edge Detection

The powerful, mains-powered monochromatic backlight helps the software to accurately detect the edges of the droplet using a Canny edge detection algorithm. The bright, uniform rectangular panel creates a larger change in pixel lightness than would otherwise occur, which ensures that a sharp edge can be found.



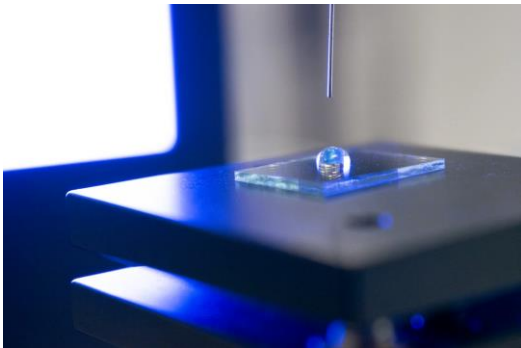
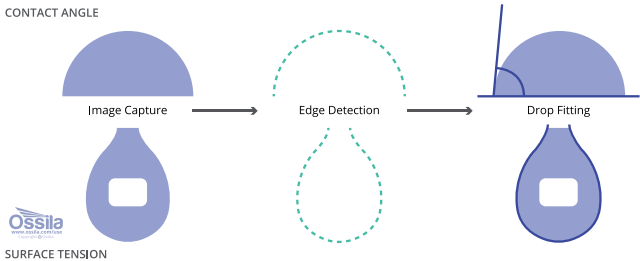
Contact Angle

For droplets with contact angles above 10°, a polynomial curve is fitted to the droplet edge. Where the curve crosses the baseline, its tangent is used to determine the contact angle. If a droplet is below 10°, then a circle fit is used for contact angle measurements instead.



Surface Tension

The software can also perform optical tensiometry measurements on droplets suspended from a needle tip. A series of droplet models are created using the droplet radius and liquid density. The models are compared with the detected edge and the closest match is used to determine the surface tension of the liquid.



| | |
|---------------------------|-------------------------|
| Measurement Accuracy | ±1° |
| Measurement Range | 5° – 180° |
| Stage Area | 50 mm x 50 mm |
| Maximum Sample Thickness | 20 mm |
| Maximum Camera Resolution | 1920 x 1080 |
| Maximum Frame Rate | 30 FPS |
| Dimensions L x W x H | 320 mm x 95 mm x 165 mm |

| | |
|-----------------|---------|
| Syringe Volume | 25 µL |
| Needle Diameter | 0.47 mm |
| Needle Length | 51 mm |
| Tip Shape | Blunt |

Optical Spectrometer



The Ossila Optical Spectrometer is an accessible system, bringing affordable UV-Vis-NIR spectroscopy to research scientists worldwide. The fully programmable, modular design fits nicely into most existing UV-Vis-NIR optical spectroscopy labs. A simple command library and trigger modes make it easy to integrate into your workflow.

The compact CCD detector, fibre optic and USB compatibility, and intuitive free software mean you can quickly start measuring the optical properties of your samples. Our versatile and modular design allows you to analyse many different samples, including solutions and thin film samples.

Buy as an independent modular spectrometer or as a part of our complete optical spectroscopy kit to get started straight away.



Powerful Electronics

High-speed 16-bit, 500 kSPS ADC



USB-C Powered

Power with your computer or laptop



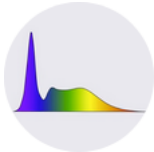
Compact Design

Lightweight and portable



Free Software

With free updates



Dynamic Spectral Range

Capable of measuring the entire visible light spectrum, from the UV-A band to near infrared. With a range of 320 nm to 1050 nm and resolution of up to 2.5 nm, our system can be used to study a wide range of materials including photovoltaic, solar cell, OLED, biological, and 2D materials.



Fast Acquisition Speeds

A powerful Arm Cortex M4 processor works with a high-speed 16-bit, 500 kSPS, analog-to-digital converter. Our system can transfer over 100 frames-per-second to the host computer when running in internal trigger mode. Plus, a six port I/O expansion header allows for easy integration with other 5V equipment.



Internal and External Trigger Modes

Use in free-running mode or integrate with other systems using the external trigger input. The rolling integration mode lets you control the integration time dynamically. With an output to synchronise acquisition with an external shutter plus two general purpose outputs, it features six I/O ports in total, including a ground port.

| | |
|-----------------------------|------------------------------|
| Wavelength Range | 320 nm – 1050 nm |
| Grating Blaze Wavelength | 500 nm |
| Resolution (FWHM) | 2.5 nm |
| Optical Input | SMA 905 fibre or free space |
| Entrance Slit Width | 25 μ m |
| Dark Noise | <50 counts |
| Signal-to-Noise Ratio | >500:1 |
| Stray Light | <0.2% |
| Detector Type (Pixels) | CCD (1600) |
| Analog-to-Digital Converter | 16-bit, 500 kSPS |
| Connection Type | USB-C |
| Communication Protocol | Serial-over-USB |
| Data Transfer Speed | Up to 100 FPS (PC dependant) |
| Dimensions L x W x H | 78 mm x 78 mm x 38 mm |
| Weight | 150 g |

LED Measurement System



The Ossila LED Measurement System provides a low cost and complete solution for performing current-voltage-luminance (IVL or JVL) characterisation of LEDs. The device holder has built-in light sensors to allow for illuminance, luminance, and white count measurements. To simplify device testing, the software will also calculate the current and power efficiency of your LED. Lifetime mode, meanwhile, measures the performance of the LED over an extended time under a constant voltage.

The system is compatible with all Ossila substrate systems, so it is easy to both fabricate and test LED devices.



LED Measurement

Performs current-voltage-luminance characterisation



Easy Installation

Simply plug in, switch on, and run the software



Wide Measurement Range

Capable of delivering voltages between -10 V and +10 V



Free Software

Intuitive PC software included



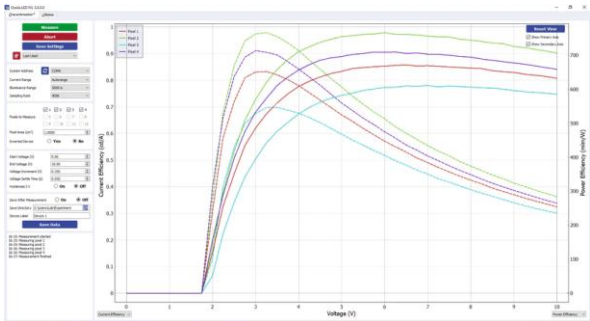
Rapid Characterisation

Our intuitive software (included) makes it easy to take current-voltage-luminance measurements. The system records illuminance, luminance and white count. To speed up the characterisation process, the system will then calculate both the current efficiency and power efficiency of your LED.



Measure Device Stability

By applying a constant voltage and measuring the current, luminance, and efficiency over an extended period of time, the stability of LEDs can be tracked and analysed.



Voltage Specifications

| Range | Accuracy | Precision | Resolution |
|-------|----------|-----------|------------|
| ±10 V | ±10 mV | 333 µV | 170 µV |

Current Specifications

| Range | Accuracy | Precision | Resolution |
|---------|----------|-----------|------------|
| ±200 mA | ±500 µA | 10 µA | 1 µA |
| ±20 mA | ±10 µA | 1 µA | 100 nA |
| ±2 mA | ±1 µA | 100 nA | 10 nA |
| ±200 µA | ±100 nA | 10 nA | 1 nA |
| ±20 µA | ±10 nA | 1 nA | 100 pA |


| | |
|----------------------|-------------------------|
| Wavelength Range | 400 nm – 1050 nm |
| Dimensions L x W x H | 300 mm x 151 mm x 50 mm |

Source Measure Unit




Designed for scientists and engineers working on the next generation of electronic devices, the Ossila Source Measure Unit is one of our most adaptable and fundamental pieces of equipment.






Flexible Communication
Connect using USB or Ethernet

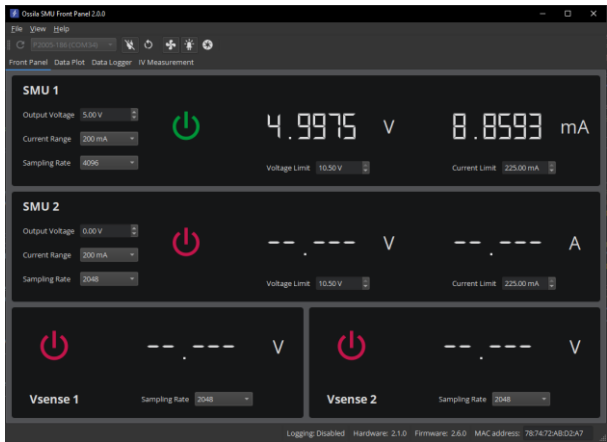

Compact and Light
Designed for space-constrained environments


Wide Measurement Range
Capable of measuring between 10 nA and 200 mA


Free Software
Easily controllable with free PC software


Five Independent Channels
Features dual source measure and voltmeter channels. Two SMU channels output voltage while measuring current and/or voltage, and two separate voltage measurement channels measure voltage sourced by external components. The shutter/trigger channel allows external control and programming.


Diverse Programming Languages
The user-friendly design works with almost any programming language. Common languages that can be used to interface to it include Python, LabVIEW™, MATLAB, Java, VB, Wolfram, C/C++, and Perl.



Voltage Source Specifications

| Range | Accuracy | Precision | Resolution |
|-------|----------|-----------|------------|
| ±10 V | ±10 mV | 333 µV | 170 µV |

Voltage Measure Specifications

| Range | Accuracy | Precision | Resolution |
|-------|----------|-----------|------------|
| ±10 V | ±10 mV | 50 µV | 10 µV |

Current Specifications

| Range | Accuracy | Precision | Resolution |
|---------|----------|-----------|------------|
| ±200 mA | ±500 µA | 10 µA | 1 µA |
| ±20 mA | ±10 µA | 1 µA | 100 nA |
| ±2 mA | ±1 µA | 100 nA | 10 nA |
| ±200 µA | ±100 nA | 10 nA | 1 nA |
| ±20 µA | ±10 nA | 1 nA | 100 pA |

| | |
|----------------------|-------------------------|
| Channel Connectors | BNC |
| Dimensions L x W x H | 185 mm x 125 mm x 55 mm |

Potentiostat



The Ossila Potentiostat is a powerful electrochemical measurement device for performing linear sweep voltammetry, cyclic voltammetry, open circuit potential, and controlled potential electrolysis. Designed for both experienced chemists and newcomers to the field, the easy-to-use PC software makes it straightforward for anyone to take accurate and precise measurements across a wide potential and current range.

Purchase with or without an electrochemical cell, non-aqueous Ag/Ag⁺ working electrode, platinum disc reference electrode, and platinum wire counter electrode. No research or teaching lab should be without an Ossila Potentiostat.



Versatile

Can be used in multiple experiments



Powerful Electronics

Capable of outputting potentials of up to 7.5 V



Compact and Light

Designed for space-constrained environments



Free Software

Intuitive PC software included



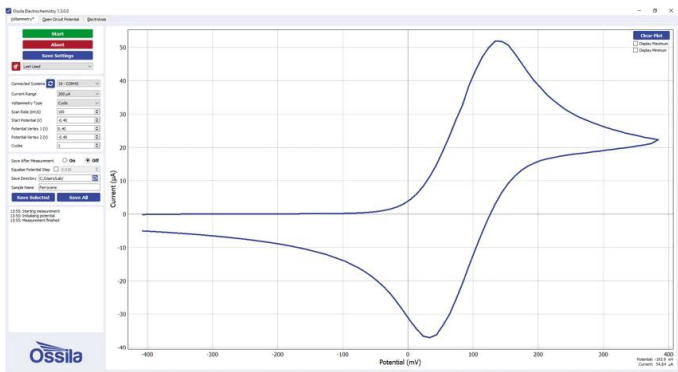
Accurate and Precise

With an applied potential accuracy and resolution of ± 10 mV and 333 μ V respectively, and a current measurement accuracy and resolution at the 20 μ A range of ± 20 nA and 5 nA, the Ossila Potentiostat is both accurate and precise.



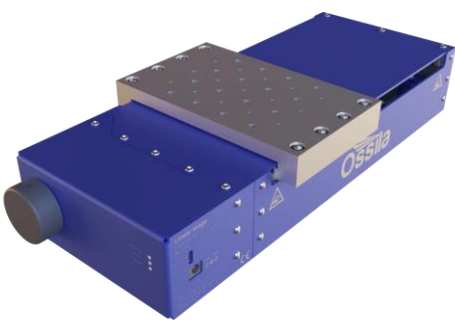
Wide Potential and Current Range

To allow for a wide range of material characterisation, the Ossila Potentiostat is capable of outputting potentials of up to 7.5 V and can measure currents over five ranges from ± 20 nA to ± 200 mA.



| | |
|--------------------------------|---|
| Potential Range | ± 7.5 V |
| Potential Compliance | ± 10 V |
| Applied Potential Accuracy | ± 10 mV offset |
| Applied Potential Resolution | 333 μ V |
| Maximum Current | ± 200 mA |
| Current Ranges | ± 20 μ A to ± 200 mA (5 ranges) |
| Current Measurement Accuracy | ± 20 nA offset (at 20 μ A range) |
| Current Measurement Resolution | 5 nA (at 20 μ A range) |
| Communication | USB-B |
| Dimensions L x W x H | 175 mm x 125 mm x 55 mm |
| Weight | 600 g |

Linear Stage



With a 50 mm to 200 mm travel distance and a precision ball screws, Ossila stages offer accurate positioning control. Calibrated according to ISO 230-2:2014 standard with our traceable calibration system.

Plus, our free motion control software detects and controls your Ossila linear stages. You can easily home your stage, move to absolute positions, move by relative distances, and set the movement speed. For even greater flexibility, control your stage directly with a serial command library.

Available in one, two, or three axis configurations.



Achieve Precision

Precise and accurate motion control



Modular Design

Combine two or three stages for multi-axis motion



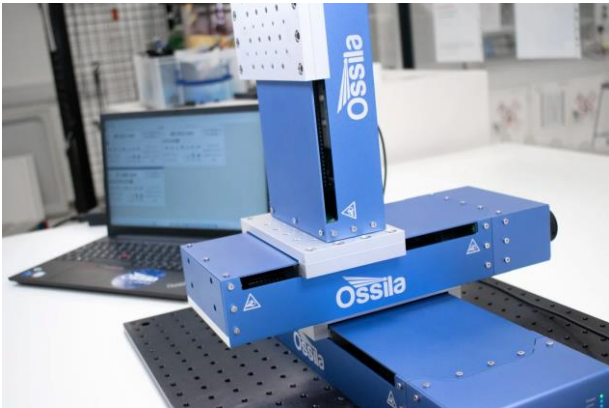
Move High Loads

Move 30 kg horizontal and 10 kg vertical loads



Free Software

Intuitive and flexible software at no extra cost



| Specification | Standard | High Precision | Compact |
|---|---------------|----------------|---------------|
| Drive | C7 ball screw | C5 ball screw | C7 ball screw |
| Travel Range Options | 100, 200 mm | 100, 200 mm | 50, 100 mm |
| Maximum Speed | 15 mm/s | 15 mm/s | 15 mm/s |
| Maximum Horizontal Load | 30 kg | 30 kg | 15 kg |
| Maximum Vertical Load | 10 kg | 10 kg | 3 kg |
| Motion Specification | Standard | High Precision | Compact |
| Maximum Reversal Error | <40 µm | <20 µm | <40 µm |
| Mean Reversal Error | <20 µm | <10 µm | <20 µm |
| Bi-directional Repeatability | <40 µm | <20 µm | <40 µm |
| Forward Repeatability | <10 µm | <5 µm | <10 µm |
| Backward Repeatability | <10 µm | <5 µm | <10 µm |
| Mean Bi-directional Positioning Error | <20 µm | <20 µm | <20 µm |
| Bi-directional Positioning Error | <40 µm | <20 µm | <40 µm |
| Forward Positioning Error | <30 µm | <15 µm | <30 µm |
| Backward Positioning Error | <30 µm | <15 µm | <30 µm |
| Bi-directional Systematic Positioning Error | <40 µm | <20 µm | <40 µm |
| Forward Systematic Positioning Error | <30 µm | <15 µm | <30 µm |
| Backward Systematic Positioning Error | <30 µm | <15 µm | <30 µm |

